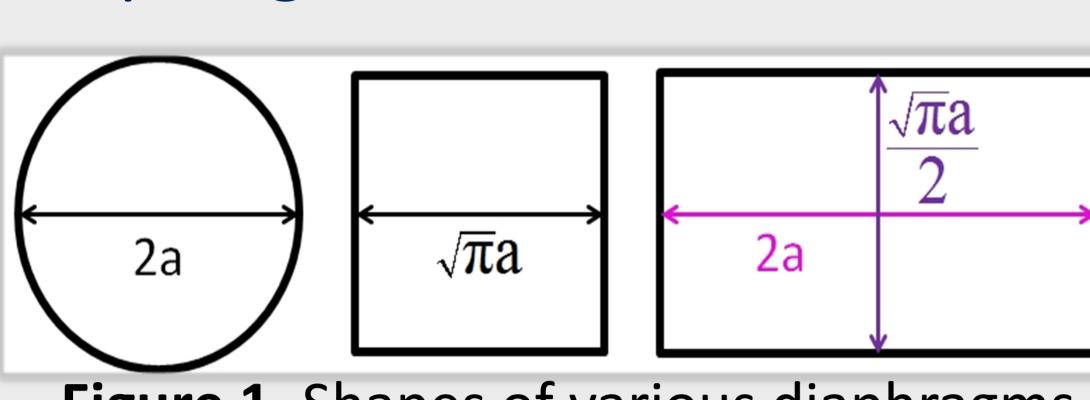
# VLSI Layout Based Design Optimization of a Piezoresistive MEMS Pressure Sensors Using COMSOL

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Introduction: From the VLSI layout perspective, to study the relation between shape of the diaphragm versus better sensitivity and reliability.



 $\begin{array}{ccc} \textbf{Diaphragm} & \textbf{Dimension} \\ \textbf{type} & \textbf{($\mu m$)} \\ \textbf{Circular} & 250 \\ \textbf{Square} & 443 \\ \textbf{Rectangle} & 396 \times 500 \\ \end{array}$ 

Figure 1. Shapes of various diaphragms
Thickness of the diaphragm 30μm.

Table 1. Dimensions

Sensor Diaphragm Design: Deflection is given by

$$\frac{\partial^4 w(x,y)}{\partial x^4} + 2\alpha_{si} \frac{\partial^4 w(x,y)}{\partial x^2 \partial y^2} + \frac{\partial^4 w(x,y)}{\partial y^4} = \frac{P}{Dh^3}$$

$$D = \frac{Eh^3}{12(1-\vartheta^2)}$$

P: Differential pressure

h: Membrane of thickness

D: Rigidity parameter

## **Application Mode Using COMSOL**

**Structural Mechanics:** Used for structural design of the model which includes pre-setting of subdomain consists of silicon as substrate/diaphragm and polysilicon as piezoresistor. Resultant deflection and stress are also studied.

Material System: Uses anisotropic models that include local and global coordinate systems.

Conductive Media DC Module: Used to investigate the changes in electrical connectivity when the piezoresistors are arranged in Wheatstone bridge configuration.

### **Results: Deflection Analysis:**

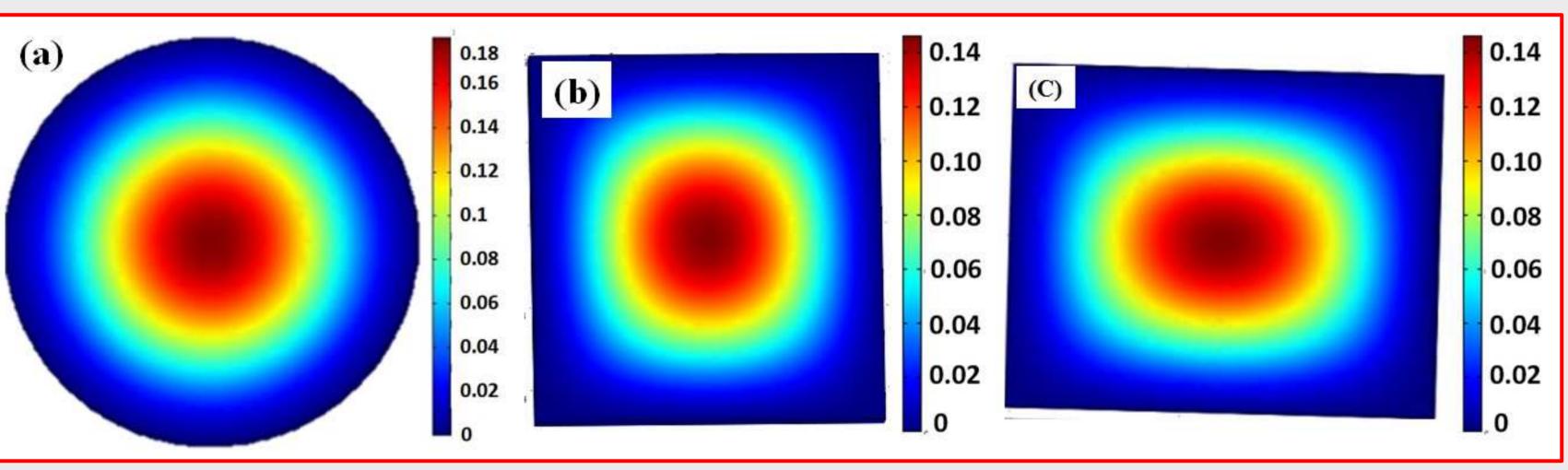
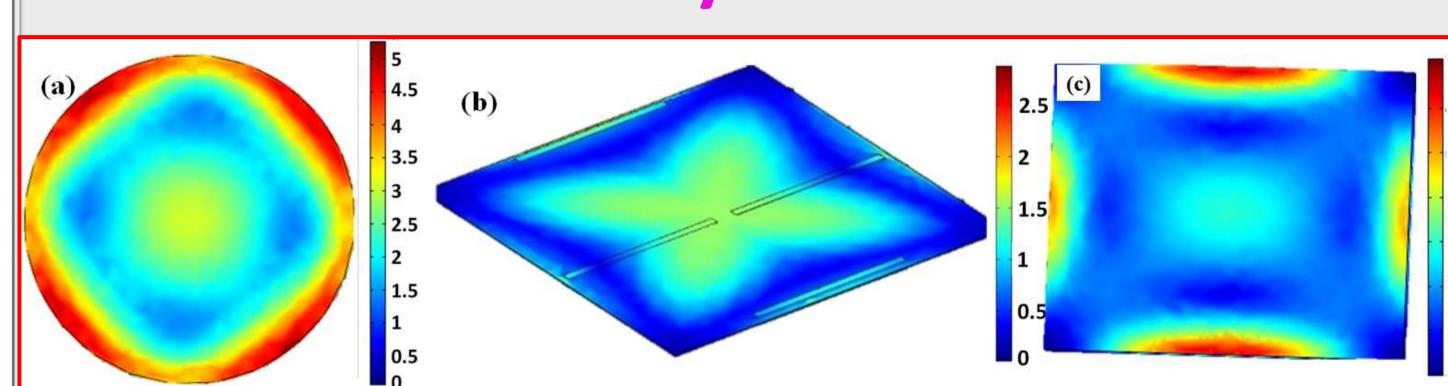


Figure 2. Comparison of deflection in (a) circular (b) square (c) rectangular diaphragms at an applied pressure of 1MPa.

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### Results: Stress Analysis:



**Figure 3.** Comparison of stress in **(a)** circular **(b)** square **(c)** rectangular diaphragms at an applied pressure of 1MPa.

#### Results: Electrical Analysis:

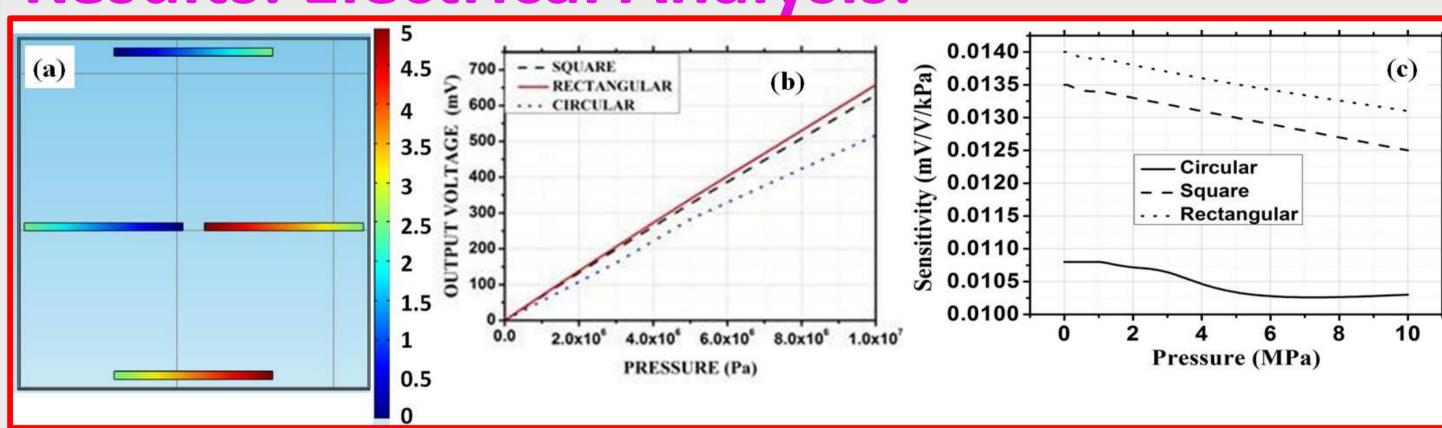


Figure 4. (a) Potential distribution in a square diaphragm (b) Wheatstone bridge output voltage and (c) Sensor output voltage sensitivity

#### **Conclusions:**

- (i) Deflection is maximum at the center of the diaphragm and minimum at edges.
- (ii) Maximum deflection is more in case of circular diaphragm when compared to the square and rectangular diaphragms.
- (iii) maximum stress position is at the edge of the diaphragm.
- (iv) Stress is much larger in a rectangular diaphragm
- (v) Sensor output voltage is smaller in the case of circular diaphragm. For square and rectangular diaphragms, the output voltage is almost same.
- (vi) From layout aspects, square or rectangular shapes are better.
- (vii) Due to more stress compared felt by rectangular diaphragm, the probability for the sensor breakdown is more.
- (viii) Square diaphragm is preferable.

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